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Modelling approaches to assess the reliability of semiconductor devices

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One research area of KAI – Kompetenzzentrum Automobil- und Industrieelektronik is the reliability of semiconductor devices. Often, the reliability is assessed by extensive testing. To save test resources, we develop lifetime models describing the degradation of the devices under application conditions. To achieve good results we research three approaches: statistical lifetime models, FEM simulation models and stochastic state-space models.

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